

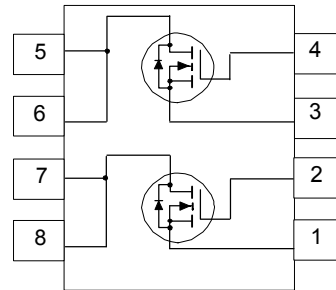
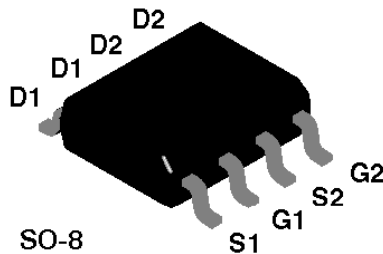
## NDS9936 Dual N-Channel Enhancement Mode Field Effect Transistor

### General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as DC/DC conversion, disk drive motor control, and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

### Features

- 5A, 30V.  $R_{DS(ON)} = 0.05\Omega$  @  $V_{GS} = 10V$ .
- High density cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.



### Absolute Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	NDS9936	Units
$V_{DSS}$	Drain-Source Voltage	30	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Drain Current - Continuous @ $T_A = 25^\circ\text{C}$ (Note 1a)	$\pm 5.0$	A
	- Continuous @ $T_A = 70^\circ\text{C}$ (Note 1a)	$\pm 4.0$	
	- Pulsed @ $T_A = 25^\circ\text{C}$	$\pm 40$	
$P_D$	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	40	$^\circ\text{C/W}$

**Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{ V}, V_{GS} = 0\text{ V}$ <div><math>T_J = 55^{\circ}\text{C}</math></div>			2	$\mu\text{A}$
					20	$\mu\text{A}$
$I_{GSSF}$	Gate - Body Leakage, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate - Body Leakage, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ <div><math>T_J = 125^{\circ}\text{C}</math></div>	1 0.7	1.4 1.1	3 2.2	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 5\text{ A}$ <div><math>T_J = 125^{\circ}\text{C}</math></div> $V_{GS} = 4.5\text{ V}, I_D = 3.9\text{ A}$ <div><math>T_J = 125^{\circ}\text{C}</math></div>		0.044 0.066 0.066 0.099	0.05 0.1 0.08 0.16	$\Omega$
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10\text{ V}, V_{DS} = 10\text{ V}$ $V_{GS} = 4.5\text{ V}, V_{DS} = 10\text{ V}$	40 20			A
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{ V}, I_D = 3.5\text{ A}$	3	8		S
DYNAMIC CHARACTERISTICS						
$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$		525		pF
$C_{oss}$	Output Capacitance			315		pF
$C_{rss}$	Reverse Transfer Capacitance			185		pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{D(ON)}$	Turn - On Delay Time	$V_{DD} = 15\text{ V}, I_D = 1\text{ A},$ $V_{GS} = 10\text{ V}, R_{GEN} = 6\text{ }\Omega$		12	30	ns
$t_r$	Turn - On Rise Time			10	25	ns
$t_{D(OFF)}$	Turn - Off Delay Time			25	50	ns
$t_f$	Turn - Off Fall Time			10	50	ns
$Q_g$	Total Gate Charge	$V_{DS} = 15\text{ V},$ $I_D = 5\text{ A}, V_{GS} = 10\text{ V}$		17	35	nC
$Q_{gs}$	Gate-Source Charge			1.5		nC
$Q_{gd}$	Gate-Drain Charge			3.7		nC

**Electrical Characteristics** (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				1.7	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.7 A (Note 2)		0.78	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>F</sub> = 5 A, dI <sub>F</sub> /dt = 100 A/μs		70	160	ns

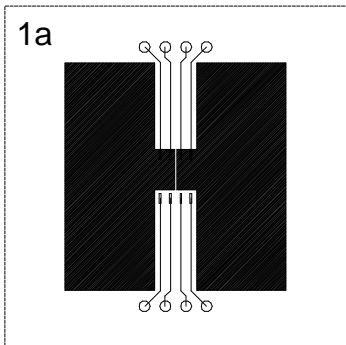
Notes:

1. R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.

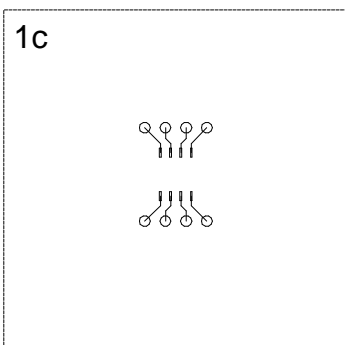
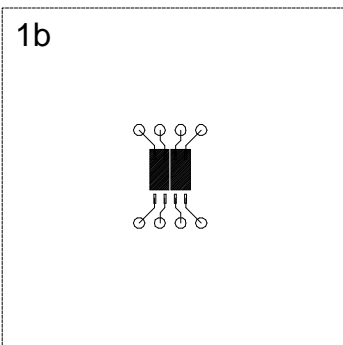
$$P_D(t) = \frac{T_J - T_A}{R_{\theta JA}} = \frac{T_J - T_A}{R_{\theta JC} + R_{\theta CA}(t)} = I_D^2(t) \times R_{DS(on)} @ T_J$$

Typical R<sub>θJA</sub> for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 78°C/W when mounted on a 0.5 in<sup>2</sup> pad of 2oz copper.
- b. 125°C/W when mounted on a 0.02 in<sup>2</sup> pad of 2oz copper.
- c. 135°C/W when mounted on a 0.003 in<sup>2</sup> pad of 2oz copper.



Scale 1 : 1 on letter size paper



2. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2.0%.

## Typical Electrical Characteristics

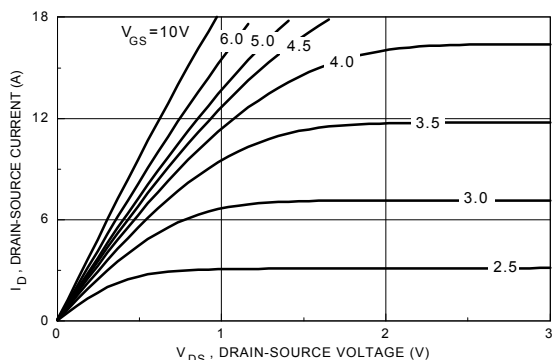


Figure 1. On-Region Characteristics.

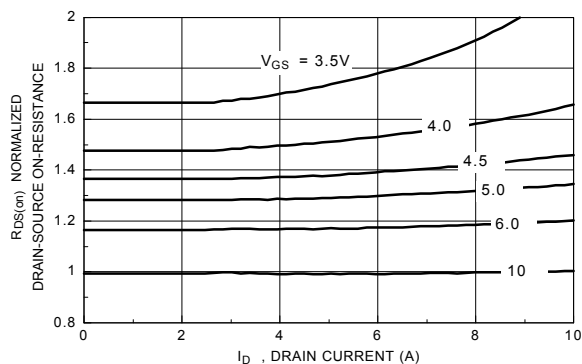


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

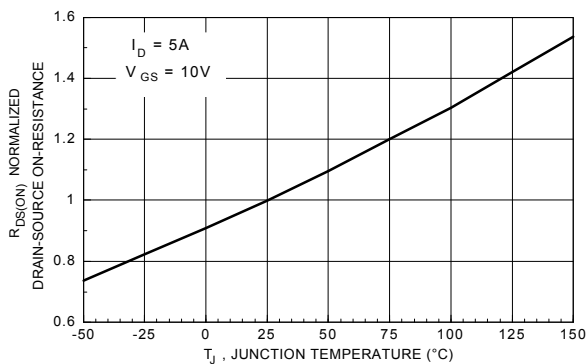


Figure 3. On-Resistance Variation with Temperature.

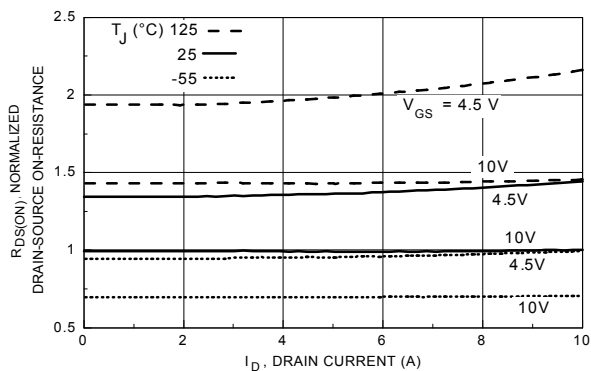


Figure 4. On-Resistance Variation with Drain Current and Temperature.

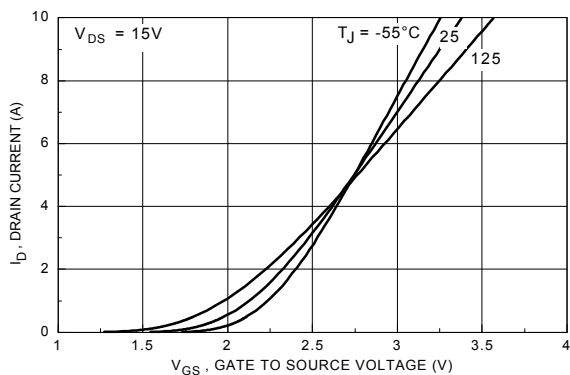


Figure 5. Transfer Characteristics.

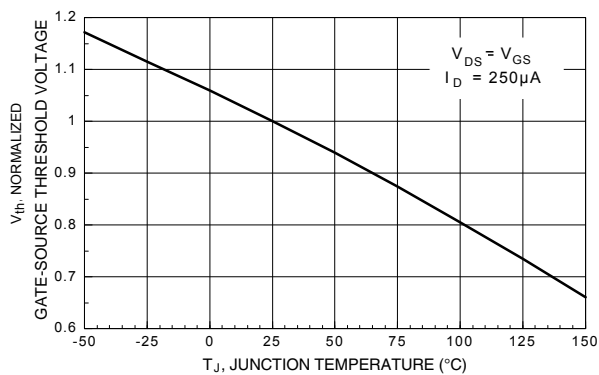
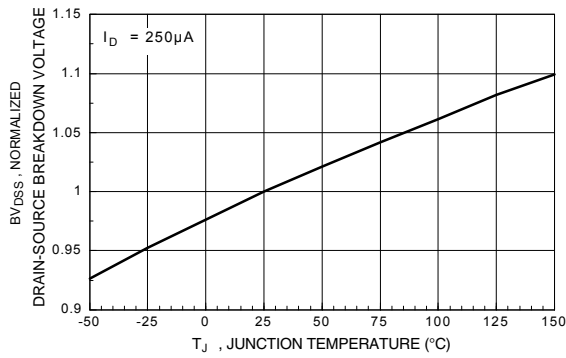
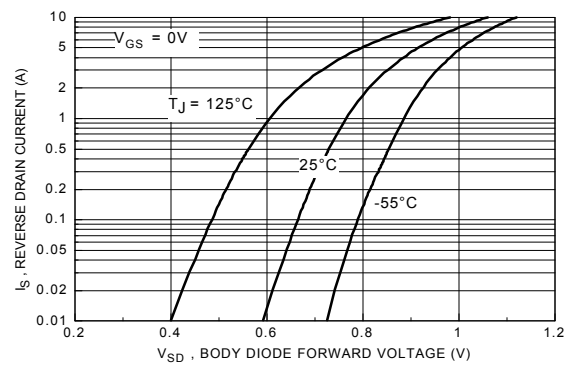


Figure 6. Gate Threshold Variation with Temperature.

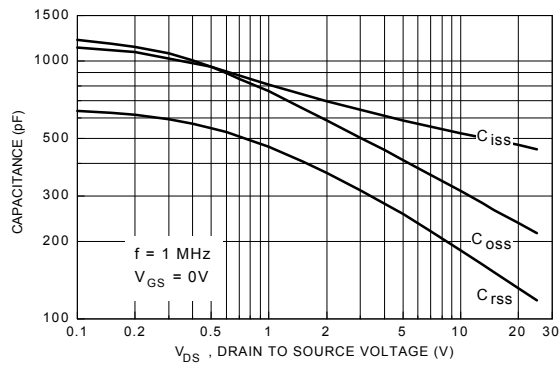
## Typical Electrical Characteristics (continued)



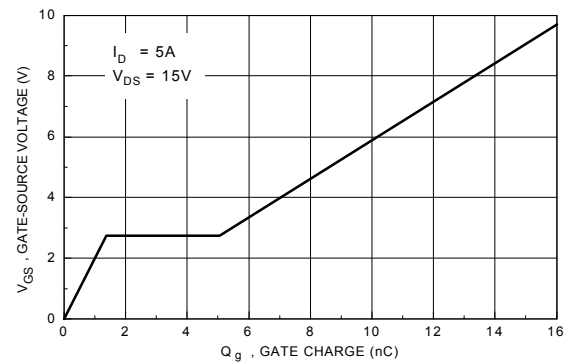
**Figure 7. Breakdown Voltage Variation with Temperature.**



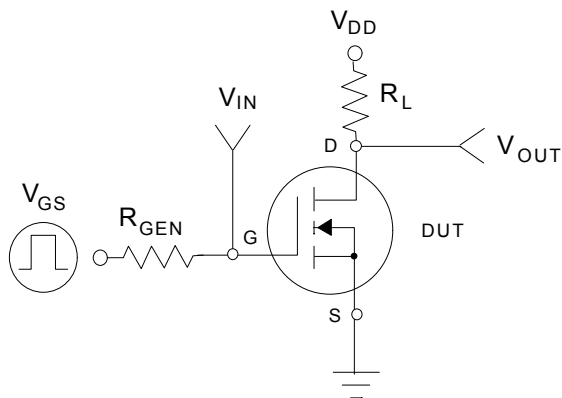
**Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.**



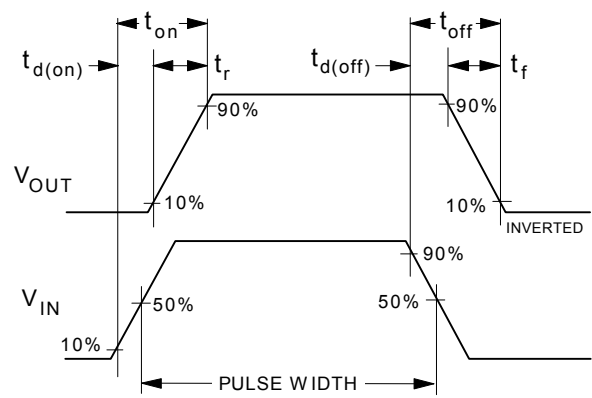
**Figure 9. Capacitance Characteristics.**



**Figure 10. Gate Charge Characteristics.**

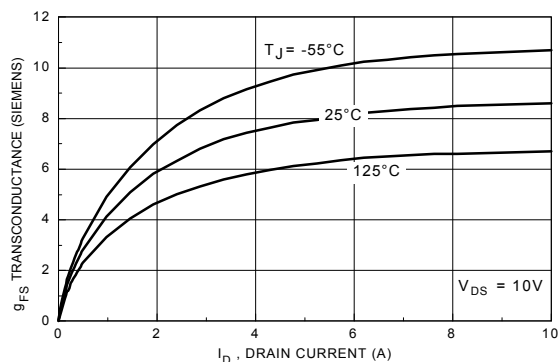


**Figure 11. Switching Test Circuit.**

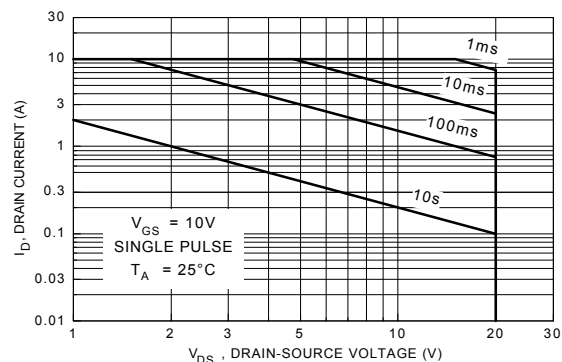


**Figure 12. Switching Waveforms.**

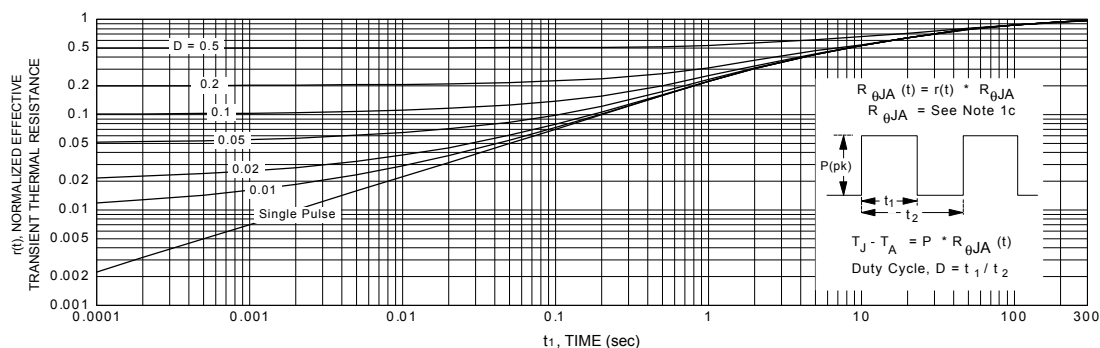
## Typical Electrical Characteristics (continued)



**Figure 13. Transconductance Variation with Drain Current and Temperature.**



**Figure 14. Maximum Safe Operating Area.**



**Figure 15. Transient Thermal Response Curve.**

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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